	Surface and Thin Films
Туре	Description
	3-D Surface Profiling
	Adhesion
AFM	Atomic Force Microscopy
AES	Auger Electron Spectroscopy
	Contact Angle Measurement
EBSD	Electron BackScatter Diffraction
ESCA	Electron Spectroscopy for Chemical Analysis Ellipsometry
	Ellipsometry
EXAFS	Extended X-ray Absorption Fine Structure
	Hardness Testing
HFS	Hydrogen Forward Scattering
ISS	Ion Scattering Spectroscopy
LA-ICPMS	Laser Ablation Inductively Coupled Plasma Mass Spec.
LEXES	Low Energy X-ray Emission Spectroscopy
	MicroHardness
	Nanoindentation
NRA	Nuclear Reaction Analysis
PIXE	Particle Induced X-Ray Emission
PALS	Positron Annihilation Lifetime Spectroscopy
	Profilometry (Contact and Non-Contact)
RBS	Rutherford Backscattering Spectrometry
SPM	Scanning Probe Microscopy
SIMS	Secondary Ion Mass Spectrometry
	Surface Roughness/Flatness
TOF-SIMS	Time-of-Flight Secondary Mass Spectrometry
TXRF	Total Reflection X-Ray Fluorescence
	Tribology
VPD-ICPMS	Vapor Phase Decomposition/ICPMS
	Wafer Bow
SurfScan	Wafer Particle Maps
	Wear & Friction
XRD	X-ray Diffraction
XRF	X-ray Fluorescence
XPS	X-ray Photoelectron Spectroscopy
XRR	X-ray Reflectivity